

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|------|-----------------------------------|---|------------------|---------|------------------|
| L5 | 6907 | necsel or vcsel | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 09:49 |
| L6 | 1000 | I5 and defect\$ | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 09:50 |
| L7 | 869 | I6 and substrate | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 09:50 |
| L8 | 810 | I7 and semiconductor | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 09:50 |
| L9 | 570 | I8 and dop\$3 | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 10:01 |
| L10 | 93 | I9 and (defect adj3 density) | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 10:52 |
| L11 | 5 | I9 and (defect adj3 density).clm. | US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 10:52 |